STD80N3LL



N-channel 30 V, 4 m Ω typ., 80 A Power MOSFET in a DPAK package

Datasheet - production data

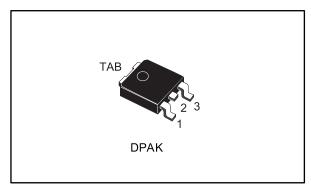
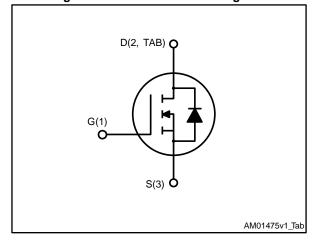


Figure 1: Internal schematic diagram



Features

Order code	V _{DS}	R _{DS(on)} max.	_{6(on)} max. I _D	
STD80N3LL	30 V	5.2 mΩ	80 A	75 W

- Very low on-resistance
- Very low gate charge
- High avalanche ruggedness
- Low gate drive power loss

Applications

• Switching applications

Description

This device is an N-channel Power MOSFET with very low $R_{\text{DS(on)}}$ in all packages.

Table 1: Device summary

Order code	Marking	Package	Packaging
STD80N3LL	80N3LL	DPAK	Tape and reel

Contents STD80N3LL

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STD80N3LL Electrical ratings

1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit	
V _{DS}	Drain-source voltage	30	V	
V_{GS}	Gate-source voltage	±20	V	
I _D ⁽¹⁾	Drain current (continuous) at T _C = 25 °C	80	Α	
I _D ⁽¹⁾	Drain current (continuous) at T _C = 100 °C	60	Α	
I _{DM} ⁽¹⁾⁽²⁾	Drain current (pulsed)	320	Α	
P _{TOT} ⁽¹⁾	Total dissipation at T _C = 25 °C	75	W	
Tj	Operating junction temperature range		°C	
T _{stg}	Storage temperature range	-55 to 175 °		

Notes:

Table 3: Thermal data

Symbol	Parameter	Value	Unit
R _{thj-pcb} ⁽¹⁾	Thermal resistance junction-pcb max.	50	°C/W
R _{thj-case}	Thermal resistance junction-case max.	2	°C/W

Notes:

⁽¹⁾This value is limited by package

⁽²⁾Pulse width limited by safe operating area

 $^{^{(1)}}$ When mounted on FR-4 board of 1 inch², 2oz Cu

Electrical characteristics STD80N3LL

2 Electrical characteristics

(T_C = 25 °C unless otherwise specified)

Table 4: On/off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	$I_D = 1 \text{ mA}, V_{GS} = 0 \text{ V}$	30			V
I _{DSS}	Zero gate voltage drain current	V _{GS} = 0 V V _{DS} = 30 V			1	μΑ
I _{GSS}	Gate-body leakage current	V _{GS} = 20 V, V _{DS} = 0 V			100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1		2.5	V
D	Static drain-source	V _{GS} = 10 V, I _D = 40 A		4	5.2	mΩ
R _{DS(on)}	on-resistance	V _{GS} = 4.5 V, I _D = 40 A		5.5	6.5	mΩ

Table 5: Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C _{iss}	Input capacitance	V 05 V 6 4 MH-	-	1640	1	
Coss	Output capacitance	V _{DS} = 25 V, f = 1 MHz, V _{GS} = 0 V		207	ı	pF
C _{rss}	Reverse transfer capacitance	VGS = 0 V	-	160	1	
Qg	Total gate charge	$V_{DD} = 15 \text{ V}, I_{D} = 80 \text{ A},$	-	18	ı	
Q_{gs}	Gate-source charge	V _{GS} = 4.5 V (see <i>Figure</i>	-	5.3	ı	nC
Q_{gd}	Gate-drain charge	14: "Test circuit for gate charge behavior")	-	8.8	1	

Table 6: Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)}	Turn-on delay time	$V_{DD} = 15 \text{ V}, I_D = 40 \text{ A},$	-	6.4	-	ns
t _r	Rise time	$R_G = 4.7 \Omega, V_{GS} = 10 V$	-	8	-	ns
t _{d(off)}	Turn-off delay time	(see Figure 13: "Test circuit for resistive load	-	36	-	ns
t _f	Fall time	switching times")	-	12	-	ns

Table 7: Source-drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{SD} ⁽¹⁾	Forward on voltage	$I_{SD} = 80 \text{ A}, V_{GS} = 0 \text{ V}$	-		1.2	V
t _{rr}	Reverse recovery time	I _D = 80 A, di/dt = 100 A/μs	-	21		ns
Qrr	Reverse recovery charge	V _{DD} = 24 V (see Figure 15: "Test circuit for inductive	-	14		nC
I _{RRM}	Reverse recovery current	load switching and diode recovery times")	-	1.3		Α

Notes:



 $^{^{(1)}}$ Pulsed: pulse duration = 300 μ s, duty cycle 1.5%

2.1 Electrical characteristics (curves)

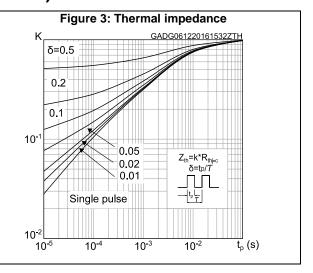
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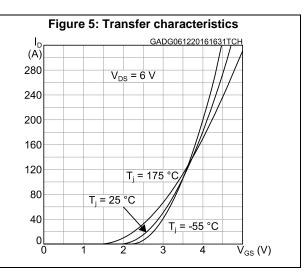
 $\overline{V}_{DS}(V)$

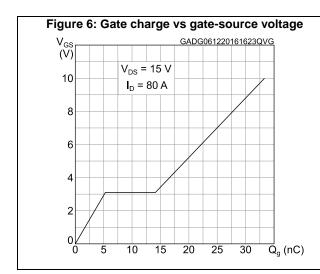
Figure 2: Safe operating area $\begin{array}{c|c} I_D \\ \hline (A) \\ \hline \\ 10^2 \\ \hline \\ 10^2 \\ \hline \\ 10^1 \\ \hline \\ 10^0 \\ \hline \\ T_j \le 175~^{\circ}C \\ \hline \\ T_c = 25~^{\circ}C \\ \hline \\ single pulse \\ \hline \\ 10^{-1} \\ \hline \end{array}$

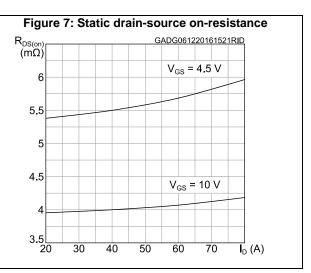
10°

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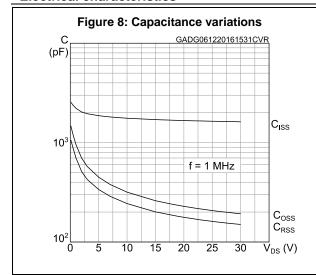
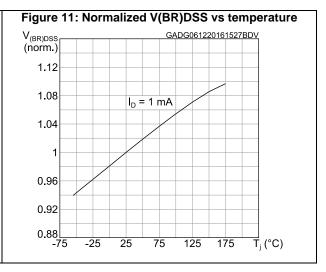
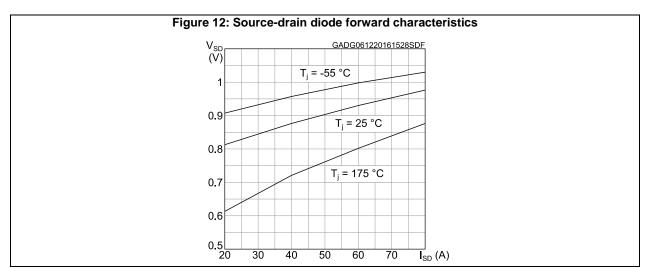


Figure 9: Normalized gate threshold voltage vs temperature V_{GS(th)} (norm.) GADG061220161526VTH 1.2 $I_D = 250 \, \mu A$ 0.8 0.6 0.4 0.2 0 -75 -25 25 125 175 T_i (°C) 75

Figure 10: Normalized on-resistance vs temperature $R_{DS(on)}$ (norm.) $V_{GS} = 10 \text{ V}$ $I_D = 40 \text{ A}$ 0.4 0.4 0.4 0.75 -25 25 75 125 175 T_j (°C)





STD80N3LL Test circuits

3 Test circuits

Figure 13: Test circuit for resistive load switching times

Figure 14: Test circuit for gate charge behavior

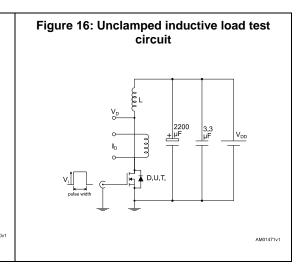
12 V 47 KΩ 100 Ω D.U.T.

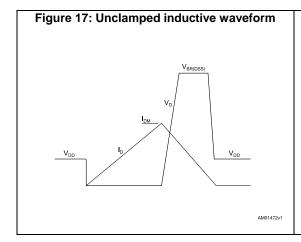
12 V 47 KΩ VG

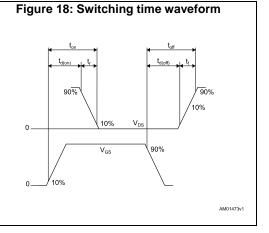
14 KΩ VG

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Figure 15: Test circuit for inductive load switching and diode recovery times







4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: **www.st.com**. ECOPACK® is an ST trademark.

STD80N3LL Package information

4.1 DPAK package information

Figure 19: DPAK (TO-252) type A2 package outline

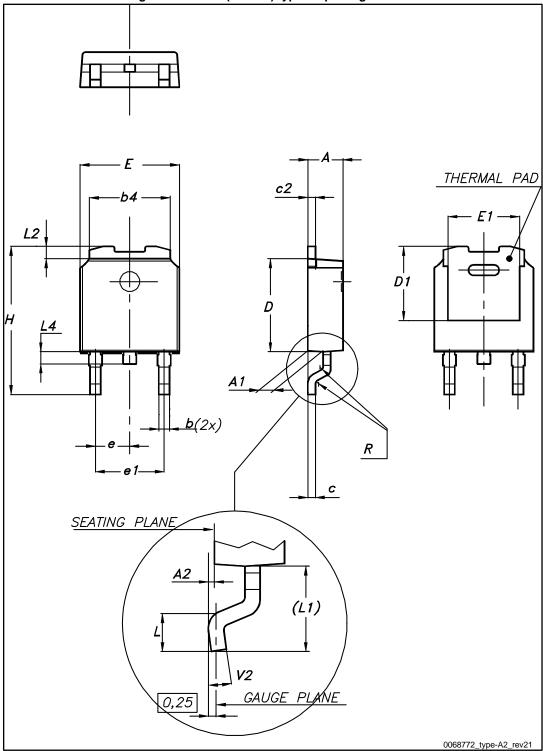


Table 8: DPAK (TO-252) type A2 mechanical data

Dim		mm	
Dim.	Min.	Тур.	Max.
A	2.20		2.40
A1	0.90		1.10
A2	0.03		0.23
b	0.64		0.90
b4	5.20		5.40
С	0.45		0.60
c2	0.48		0.60
D	6.00		6.20
D1	4.95	5.10	5.25
Е	6.40		6.60
E1	5.10	5.20	5.30
е	2.16	2.28	2.40
e1	4.40		4.60
Н	9.35		10.10
L	1.00		1.50
L1	2.60	2.80	3.00
L2	0.65	0.80	0.95
L4	0.60		1.00
R		0.20	
V2	0°		8°

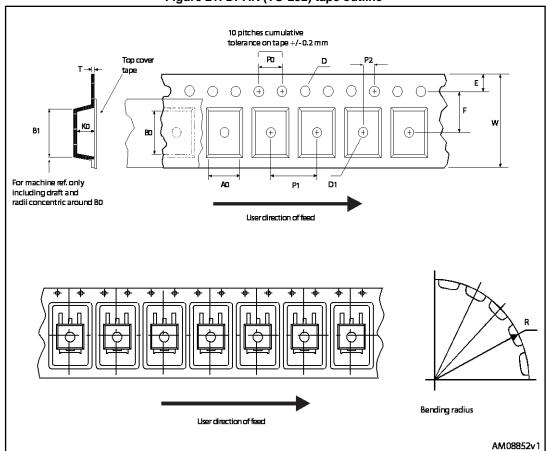
Figure 20: DPAK (TO-252) type A2 recommended footprint (dimensions are in mm)



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4.2 DPAK (TO-252) packing information

Figure 21: DPAK (TO-252) tape outline



A 40mm min. access hole at slot location

Tape slot in core for tape start 2.5mm min.width

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Figure 22: DPAK (TO-252) reel outline

Table 9: DPAK (TO-252) tape and reel mechanical data

Таре				Reel	
Dim	n	ım	Dim	1	nm
Dim.	Min.	Max.	Dim.	Min.	Max.
A0	6.8	7	А		330
В0	10.4	10.6	В	1.5	
B1		12.1	С	12.8	13.2
D	1.5	1.6	D	20.2	
D1	1.5		G	16.4	18.4
Е	1.65	1.85	N	50	
F	7.4	7.6	Т		22.4
K0	2.55	2.75			
P0	3.9	4.1	Bas	e qty.	2500
P1	7.9	8.1	Bul	k qty.	2500
P2	1.9	2.1			
R	40				
Т	0.25	0.35			
W	15.7	16.3			

Revision history STD80N3LL

5 Revision history

Table 10: Document revision history

Date	Revision	Changes
26-Jul-2016	1	First release.
06-Dec-2016	2	Document status promoted from preliminary to production data. Updated Section 2: "Electrical characteristics" and added Section 2.1: "Electrical characteristics (curves)". Minor text changes.

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